SEI Releases 2017 Emerging Technology Domains Risk Survey

To support the mission of US-CERT, the CERT Coordination Center (CERT/CC) located at Carnegie Mellon University’s Software Engineering Institute was tasked with studying emerging systemic vulnerabilities, which are defined as exposures or weaknesses in a system that arise due to complex or unexpected interactions between subcomponents. The CERT/CC researched the emerging technology trends through 2025 to assess the technology domains that will become successful and transformative, as well as the potential cybersecurity impact of each domain. This report is intended to provide a brief background of each emerging technology domain along with a discussion of potential vulnerabilities and the risks of compromise or failure within each domain.

This report covers new or changed domains observed since the release of the CERT/CC 2016 Emerging Technology Domains Risk Survey. This list does not supersede previous reports, and many of the previously reviewed domains remain important. This report can be considered an addendum to the earlier report.

This report also identifies three domains that must be considered high priorities for outreach and analysis in 2017:

1. Intelligent Transportation Systems
2. Machine Learning
3. Smart Robots

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